Search	Notes

Application No.	Applicant(s)	
10/043,627	CHEN ET AL.	
Examiner	Art Unit	
Hona Liu	1624	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
546	451		
SIK	314	4/29/04	HU

	DATE	EXMF
View patent No. 6,566,384		
6608,104 for method claims		!
involving MMP-associated disorders		
burenta name secuch	4/29/04	H.C.